[1743/188]

## IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re application of

Kazutoshi KAJI, et al.

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Serial No.

Not Yet Assigned

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Filing Date

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4-5-00

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ELEMENT MAPPING UNIT, SCANNING TRANSMISSION ELECTRON MICROSCOPE, AND ELEMENT MAPPING

METHOD

## PRELIMINARY AMENDMENT

Please amend the above-identified application as follows:

## In the claims:

Please amend the following claims:

8. (Amended) A scanning transmission electron microscope, equipped with the element mapping unit according to Claim 1, that irradiates electron beams onto an object to be analyzed and supplies the electron beams, which have transmitted through the object to be analyzed, to the element mapping unit.

## REMARKS

This Preliminary Amendment is being submitted to eliminate multiple dependent claims.

It is respectfully submitted that the subject matter of the present application is new, non-obvious, and useful. Prompt consideration and allowance of the application are respectfully requested.

Attached hereto is a marked-up version of the changes made to the title by the current amendment. The attached page is captioned "Versions with markings to show changes made."

Respectfully submitted,

Dated: Jan 1 200 1

By: Silved W Greason

Reg. No. 18,918 KENYON & KENYON

One Broadway

New York, NY 10004

Telephone No. (212) 425-7200 Facsimile No. (212)425-5288

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